

Docket No.: SHIGA7.051APC

Customer No. 20,995

AP20 Rec'd PCT/PTO 25 MAY 2006

INFORMATION DISCLOSURE STATEMENT

Applicant : Takeshita et al.
App. No : Unknown
Filed : Filed Herewith
For : POSITIVE RESIST COMPOSITION
AND METHOD FOR FORMING
RESIST PATTERN
Examiner : Unassigned
Art Unit : Unknown

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

May 25, 2006

(Date)

Neil S. Bartfeld, Ph.D., Reg. No. 39,901

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application is a PTO/SB/08 Equivalent listing 21 references to be considered by the Examiner. Also enclosed are 14 foreign patent references and/or non-patent literature as listed on the Information Disclosure Statement.

This Information Disclosure Statement is being filed within three months of the filing date, with an RCE or before receipt of a first office action after an RCE and no fee is required.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: May 25, 2006

By:

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Multiple sheets used when necessary)

SHEET 1 OF 1

Application No.	Unknown 10/580,768
Filing Date	Filed Herewith 05/25/2006
First Named Inventor	Masaru Takeshita (S) (U) (C)
Art Unit	Unknown 1795
Examiner	Unsigned Anca Eoff
Attorney Docket No.	SHIGA7.051APC

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
/A.E./	1	2001/0014428 A1	08-16-2001	Uetani et al.	
	2	5,843,624	12-01-1998	Lucent Technologies Inc.	
	3	5,968,713	10-19-1999	Fujitsu Ltd.	
	4	6,004,720	12-21-1999	Fujitsu Ltd.	
	5	6,479,211 B1	11-12-2002	Sato et al.	
	6	6,656,659 B1	12-02-2003	Fujitsu Ltd.	
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FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
/A.E./	8	JP 04-039665	02-10-1992	Fujitsu Ltd.		Abstract
	9	JP 05-346668	12-27-1993	Fujitsu Ltd.		Abstract
	10	JP 09-090637	04-04-1997	Fujitsu Ltd.		Abstract
	11	JP 10-161313	06-19-1998	Fujitsu Ltd.		Abstract
	12	JP 2000-235263	08-29-2000	Tokyo Ohka Kogyo Co., Ltd.		Abstract
	13	JP 2000-310859	11-07-2000	Tokyo Ohka Kogyo Co., Ltd.		Abstract
	14	JP 2001-188347	07-10-2001	JSR Corp.		Abstract
	15	JP 2001-356483	12-26-2001	Tokyo Ohka Kogyo Co., Ltd.		Abstract
	16	JP 2002-145954	05-22-2002	Daicel Chem. Ind. Ltd.		Abstract
	17	JP 2003-005374	01-08-2003	Fuji Photo Film Co. Ltd.		Abstract
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	19	EP 0 982 628 A2	03-01-2000	Fujishima et al.		
	20	EP 1 452 917 A1	11-29-2002	Kubota et al.		
/A.E./	21	EP 1 452 919 A1	09-01-2004	Fujimura et al.		

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Examiner Signature	/Anca Eoff/	Date Considered	05/19/2008
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

T¹ - Place a check mark in this area when an English language Translation is attached.